

<b>Notice of References Cited</b>	Application/Control No. 10/530,507	Applicant(s)/Patent Under Reexamination TIKKA ET AL.	
	Examiner Barbara Summons	Art Unit 2817	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,927,649	08-2005	Metzger et al.	333/133
*	B	US-6,885,260	04-2005	Nishimura et al.	333/133
*	C	US-7,194,247	03-2007	Tikka et al.	455/339
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	WO 02/093763	11-2002	PCT	Nishimura et al.	-----
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Penunuri et al.; "RF Filter Design Using LTCC And Thin Film BAW Technology"; 2001 IEEE Ultrasonics Symposium; Vol. 1, October 2001, pp. 273-278.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.